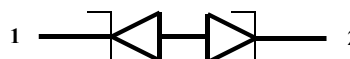
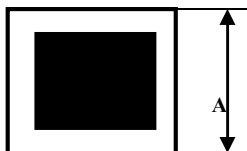


Chip Bi- directional TVS diode on 4'' Wafer.



Mechanical data: $A_x = 210\mu\text{m}$. $A_y = 210\mu\text{m}$.

Chip thickness: a) $138 \pm 12\mu\text{m}$ – for SMB-3.3L51;
b) without grinding $470 \pm 20\mu\text{m}$ – for SMB-3.3L52.

Top Metal: Al- for wire bonding.

Back side: a) Ti-Ni-Ag for Soldering – for SMB-3.3L51
b) without metallization – for SMB-3.3L52

Scribe Line Width – $40\mu\text{m}$.

Sampling testing: no bad dice inking;
guaranteed good dice quantity $\geq 95\%$.

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Working Peak Reverse Voltage	V_{RWM}		3,3.	V
Peak Pulse Power	P_{pp}	$t_p = 8/20\mu\text{s}$	48*	W
Peak Pulse Current	I_{pp}	$t_p = 8/20\mu\text{s}$	4,0*	A
Electrostatic Discharge	V_{ESD}	IEC 61000-4-2, level 4.	+/-8,0 (Contact); +/-15,0 (Air).	kV
Max.junction temperature	T_j		+150	°C

Characteristics $T_j = 25^\circ\text{C}$.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_R	Diode reverse leakage current.	$V = \pm 3,3 \text{ V}$	-	0,05	0,40	μA
V_{PT}	Punch-Through Voltage	$I_{PT} = 2\mu\text{A}$	3,5	-	-	V
V_{sb}	Snap-Back Voltage	$I_{sb} = 50\text{mA}$	2,8	-	-	V
C_j	Diode capacitance .	$f = 1\text{MHz}$, $V_{dc} = 0 \text{ V}$.	-	-	7,0	pF
V_{CL}	clamping voltage	$I_{pp} = 1,0\text{A}$; $I_{pp} = 4,0\text{A}$; $t_p = 8/20\mu\text{s}$.	-	-	9,0* 12,0*	V

*For Device testing.